

TOSHIBA Photocoupler GaAlAs Ired &amp; Photo-IC

# TLP114A

Digital Logic Isolation.

Line Receiver.

Power Supply Control Feedback Control.

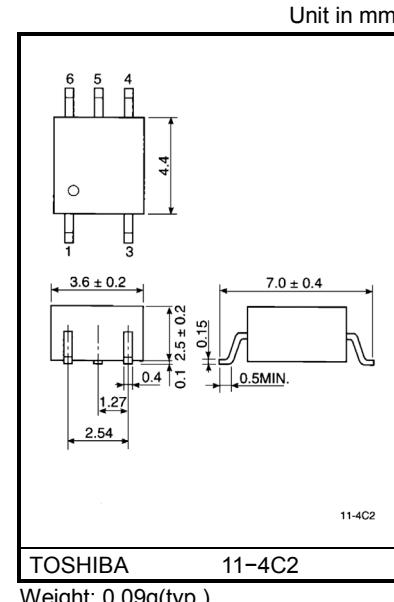
Switching Power Supply.

Transistor Invertor.

The TOSHIBA mini flat coupler TLP114A is a small outline coupler, suitable for surface mount assembly.

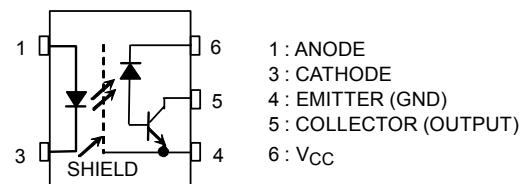
TLP114A consists of a high output power GaAlAs light emitting diode, optically coupled to a high speed detector of one chip photodiode-transistor.

- Isolation voltage: 3750 Vrms (min.)
- Switching speed:  $t_{pHL} = 0.8\mu s$ ,  $t_{pLH} = 0.8\mu s$  (max.)  
( $R_L = 1.9\text{ k}\Omega$ )
- TTL compatible
- UL recognized: UL1577, file no. E67349

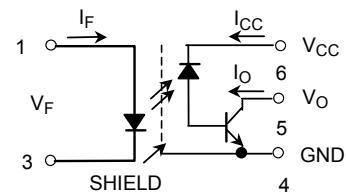


Weight: 0.09g(typ.)

## Pin Configuration (top view)



## Schematic



**Maximum Ratings (Ta = 25°C)**

| Characteristic                              |  | Symbol            | Rating  | Unit |
|---|--|-------------------|---------|------|
| LDE   | Forward current<br>(Note 1)                | I <sub>F</sub>    | 20      | mA   |
|   | Pulse forward current<br>(Note 2)          | I <sub>FP</sub>   | 40      | mA   |
|   | Peak transient forward current<br>(Note 3) | I <sub>FP</sub> T | 1       | A    |
|   | Reverse voltage                            | V <sub>R</sub>    | 5       | V    |
| Detector                                    | Output current                             | I <sub>O</sub>    | 8       | mA   |
|   | Peak output current                        | I <sub>OP</sub>   | 16      | mA   |
|   | Supply voltage                             | V <sub>CC</sub>   | -0.5~30 | V    |
|   | Output voltage                             | V <sub>O</sub>    | -0.5~20 | V    |
|   | Output power dissipation<br>(Note 4)       | P <sub>O</sub>    | 100     | mW   |
| Operating temperature range                 |  | T <sub>opr</sub>  | -55~100 | °C   |
| Storage temperature range                   |  | T <sub>stg</sub>  | -55~125 | °C   |
| Lead solder temperature(10 sec.)            |  | T <sub>sol</sub>  | 260     | °C   |
| Isolation Voltage<br>(AC,1 min., R.H.≤ 60%) |  | BV <sub>S</sub>   | 3750    | Vrms |

(Note 1) Derate 0.36mA / °C above 70°C.

(Note 2) 50% duty cycle, 1ms pulse width.

Derate 0.72mA / °C above 70°C.

(Note 3) Pulse width≤ 1μs, 300pps.

(Note 4) Derate 1.8mW / °C above 70°C.

Electrical Characteristics ( $T_a = 25^\circ\text{C}$ )

| Characteristic |   | Symbol                    | Test Condition  | Min.               | Typ.      | Max. | Unit                         |
|----------------|---|---------------------------|---|--------------------|-----------|------|------------------------------|
| LDE            | Forward voltage                           | $V_F$                     | $I_F = 16\text{mA}$   | 1.22               | 1.42      | 1.72 | V                            |
|                | Forward voltage temperature coefficient   | $\Delta V_F / \Delta T_a$ | $I_F = 16\text{mA}$   | —                  | -2        | —    | $\text{mV} / ^\circ\text{C}$ |
|                | Reverse current                           | $I_R$                     | $V_R = 3\text{V}$   | —                  | —         | 10   | $\mu\text{A}$                |
|                | Capacitance between terminals             | $C_T$                     | $V_F = 0, f = 1\text{MHz}$  | —                  | 30        | —    | pF                           |
| Detector       | High level output current                 | $I_{OH} (1)$              | $I_F = 0\text{mA}, V_{CC} = V_O = 5.5\text{V}$  | —                  | 3         | 500  | nA                           |
|                |   | $I_{OH} (2)$              | $I_F = 0\text{mA}, V_{CC} = 30\text{V}$<br>$V_O = 20\text{V}$                         | —                  | —         | 5    | $\mu\text{A}$                |
|                |   | $I_{OH}$                  | $I_F = 0\text{mA}, V_{CC} = 30\text{V}$<br>$V_O = 20\text{V}, T_a = 70^\circ\text{C}$ | —                  | —         | 50   |                              |
|                | High level supply current                 | $I_{CCH}$                 | $I_F = 0\text{mA}, V_{CC} = 30\text{V}$   | —                  | 0.01      | 1    | $\mu\text{A}$                |
| Coupled        | Current transfer ratio                    | $I_O / I_F$               | $I_F = 16\text{mA}, V_{CC} = 4.5\text{V}$<br>$V_O = 0.4\text{V}$                      | 20                 | —         | —    | %                            |
|                | Low level output voltage                  | $V_{OL}$                  | $I_F = 16\text{mA}, V_{CC} = 4.5\text{V}$<br>$I_O = 2.4 \text{ mA}$                   | —                  | —         | 0.4  | V                            |
|                | Isolation resistance                      | $R_S$                     | $R.H. \leq 60\%, V_S = 500\text{V}$<br>(Note 5)                                       | $5 \times 10^{10}$ | $10^{14}$ | —    | $\Omega$                     |
|                | Stray capacitance between input to output | $C_S$                     | $V_S = 0, f = 1\text{MHz}$<br>(Note 5)  | —                  | 0.8       | —    | pF                           |

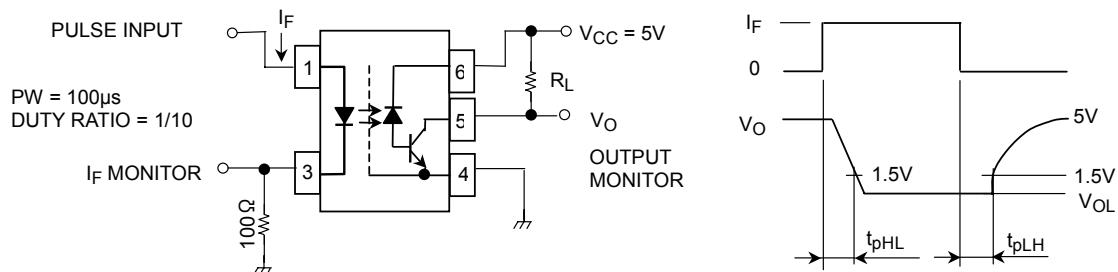
Switching Characteristics ( $T_a = 25^\circ\text{C}, V_{CC} = 5\text{V}$ )

| Characteristic                                      | Symbol    | Test Circuit | Test Condition   | Min.  | Typ.   | Max. | Unit                     |
|---|-----------|--------------|--|-------|--------|------|--------------------------|
| Propagation delay time ( $H \rightarrow L$ )        | $t_{pHL}$ | 1            | $I_F = 0 \rightarrow 16\text{mA}$<br>$V_{CC} = 5\text{V}, R_L = 1.9\text{k}\Omega$       | —     | —      | 0.8  | $\mu\text{s}$            |
| Propagation delay time ( $L \rightarrow H$ )        | $t_{plH}$ | 1            | $I_F = 16 \rightarrow 0\text{mA}$<br>$V_{CC} = 5\text{V}, R_L = 1.9\text{k}\Omega$       | —     | —      | 0.8  | $\mu\text{s}$            |
| Common mode transient immunity at high output level | $C_{MH}$  | 2            | $I_F = 0\text{mA},$<br>$V_{CM} = 400\text{V}_{\text{p-p}}$<br>$R_L = 4.1\text{k}\Omega$  | 5000  | 10000  | —    | $\text{V} / \mu\text{s}$ |
| Common mode transient immunity at low output level  | $C_{ML}$  | 2            | $I_F = 16\text{mA},$<br>$V_{CM} = 400\text{V}_{\text{p-p}}$<br>$R_L = 4.1\text{k}\Omega$ | -5000 | -10000 | —    | $\text{V} / \mu\text{s}$ |

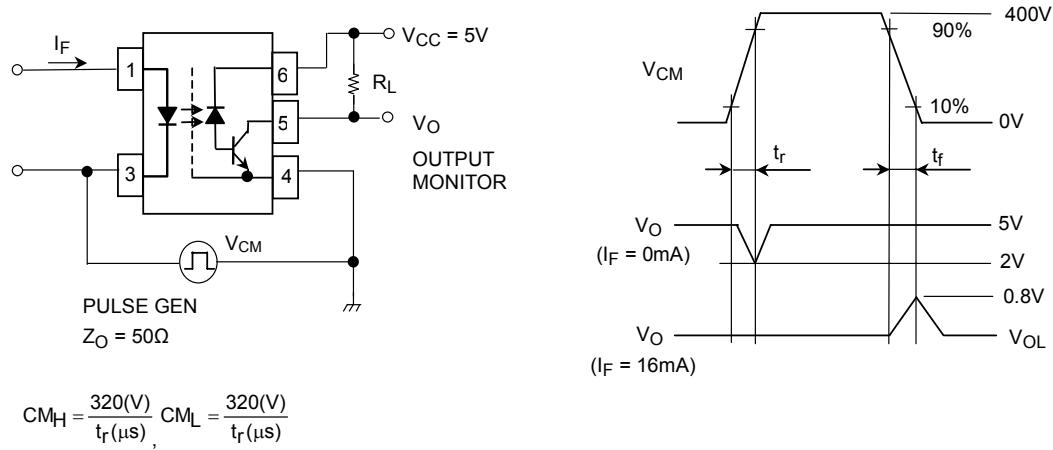
(Note 5) Device considered a two-terminal device: Pins 1 and 3 shorted together, and pins 4, 5 and 6 shorted together.

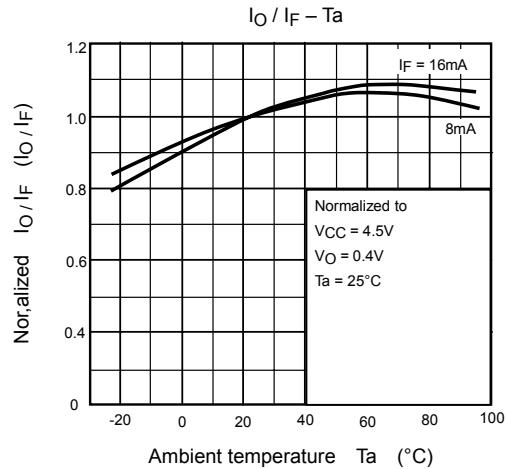
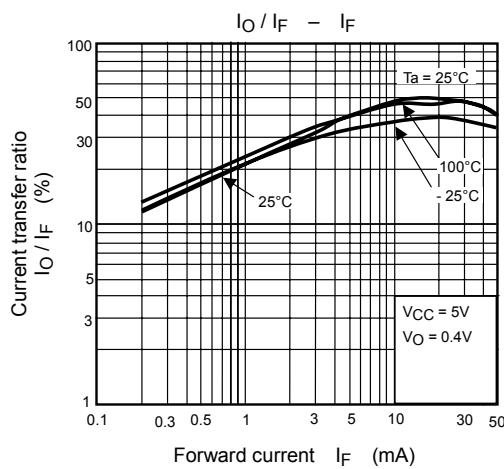
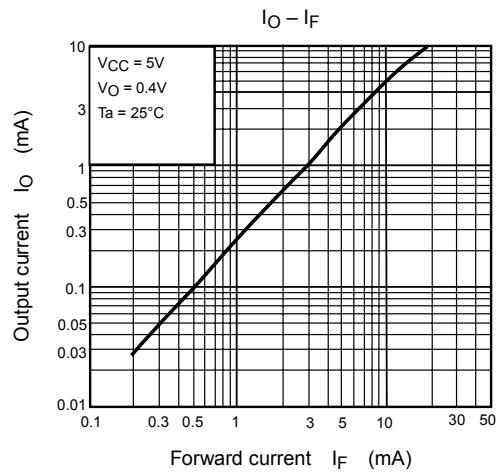
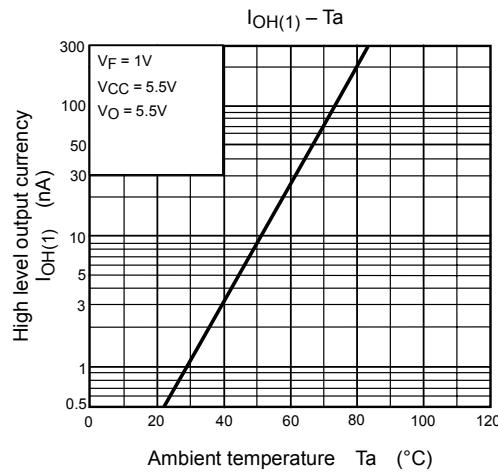
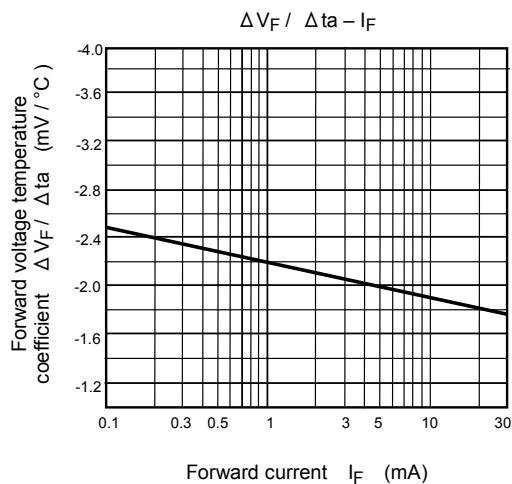
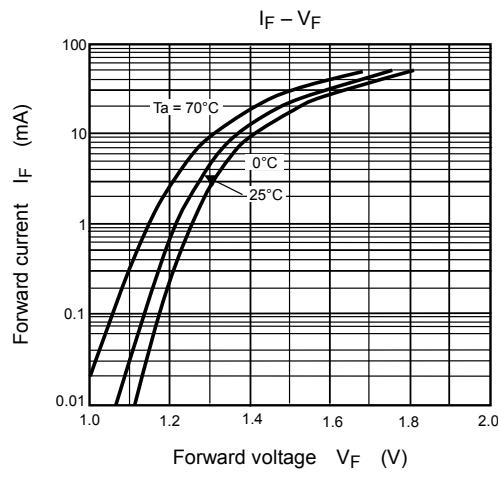
(Note 6) Maximum electrostatic discharge voltage for any pins: 100V(C=200pF, R=0)

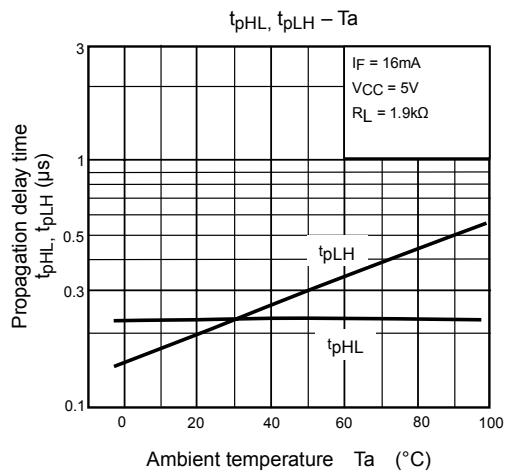
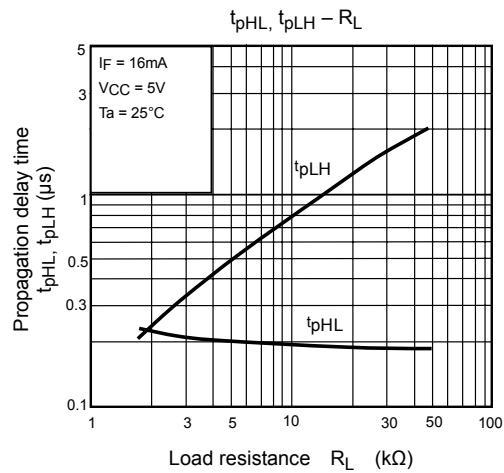
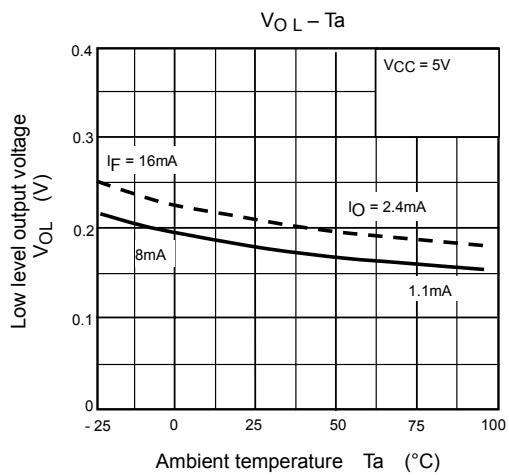
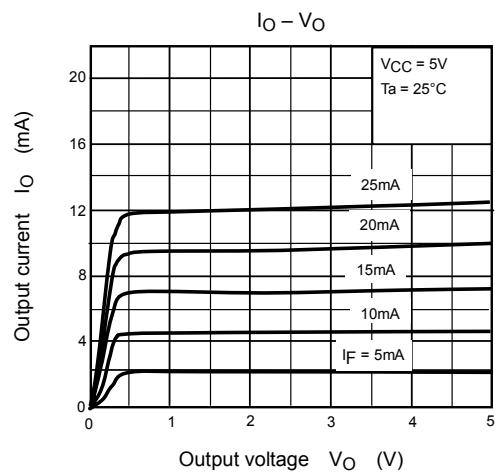
### Test Circuit 1: Switching Time Test Circuit



### Test Circuit 2: Common Mode Transient Immunity Test Circuit







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